

PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT4068930

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT
CONVEYING PARTY DATA	
Name	Execution Date
SUVOLTA, INC.	02/27/2015
RECEIVING PARTY DATA	
Name:	MIE FUJITSU SEMICONDUCTOR LIMITED
Street Address:	2000 MIZONO
City:	TADO-CHO, KUWANA, MIE
State/Country:	JAPAN
Postal Code:	511-0118
PROPERTY NUMBERS Total: 1	
Property Type	Number
Application Number:	15272113
CORRESPONDENCE DATA	
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<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>	
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ATTORNEY DOCKET NUMBER:	083852.0367
NAME OF SUBMITTER:	ELODY TIGNOR
SIGNATURE:	/Elody Tignor/
DATE SIGNED:	09/26/2016
Total Attachments: 17	
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EXHIBIT B

FORM OF PATENT ASSIGNMENT

PATENT ASSIGNMENT

This PATENT ASSIGNMENT ("Assignment") is made as of 2/27, 2015, to effectuate an assignment of certain patent assets from SuVolta, Inc., a Delaware corporation having a principal address at 130 D Knowles Drive, Los Gatos, CA 95032, USA ("Assignor") to MIE FUJITSU SEMICONDUCTOR LIMITED, a Japanese corporation having its principal place of business at 2000 Mizono, Tado-cho, Kuwana, Mie 511-0118, Japan ("Assignee").

WHEREAS, Assignor is the owner of the patents and patent applications (the "Assigned Patents") stated in Exhibit A attached to the Agreement.

WHEREAS, Assignor and Assignee have entered into an IPR PURCHASE AGREEMENT ("Agreement") dated 2/27/2015, pursuant to which Assignor has agreed, *inter alia*, to grant and assign all of Assignor's right, title and interest in and to the Assigned Patents to Assignee, and Assignee desires to acquire the entire right, title and interest in and to the Assigned Patents.

NOW, THEREFORE, for good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, Assignor and Assignee agree as follows.

1. Assignor hereby irrevocably sells, transfers, conveys and assigns unto Assignee, its successors and assigns, Assignor's entire right, title and interest in and to the Assigned Patents and any continuations, divisions, reissues, or extensions of the Assigned Patents.
2. Assignor hereby authorizes the United States Patent and Trademark Office and foreign patent and trademark offices to issue any patents from patent applications of the Assigned Patents, with the right, title and interest to be held by Assignee, Assignee's successors and assigns.

Agreed.

Assignor
SuVolta, Inc.

By: 

Name: Naomi Obinata

Title: Legal Counsel, SuVolta

Date: 3/3/2015

Assignee

Mie Fujitsu Semiconductor Limited

By: 

Name: Hayashi Yagi

Title: President and Representative Director

Date: 2/27/2015

CALIFORNIA ALL-PURPOSE ACKNOWLEDGMENT

CIVIL CODE § 1189

A notary public or other officer completing this certificate verifies only the identity of the individual who signed the document to which this certificate is attached, and not the truthfulness, accuracy, or validity of that document.

State of California)
County of Santa Clara)
On 03/03/2015 before me, DAVID JOSEPH BOUSQUET, NOTARY PUBLIC,
Date Here Insert Name and Title of the Officer
personally appeared Naomi Obihata,
Name(s) of Signer(s)

who proved to me on the basis of satisfactory evidence to be the person(s) whose name(s) is/are subscribed to the within instrument and acknowledged to me that he/she/they executed the same in his/her/their authorized capacity(ies), and that by his/her/their signature(s) on the instrument the person(s), or the entity upon behalf of which the person(s) acted, executed the instrument.

I certify under PENALTY OF PERJURY under the laws of the State of California that the foregoing paragraph is true and correct.

WITNESS my hand and official seal.



Signature [Handwritten Signature]
Signature of Notary Public

Place Notary Seal Above

OPTIONAL

Though this section is optional, completing this information can deter alteration of the document or fraudulent reattachment of this form to an unintended document.

Description of Attached Document

Title or Type of Document: _____ Document Date: _____
Number of Pages: _____ Signer(s) Other Than Named Above: _____

Capacity(ies) Claimed by Signer(s)

Signer's Name: Naomi Obihata
 Corporate Officer -- Title(s): _____
 Partner -- Limited General
 Individual Attorney in Fact
 Trustee Guardian or Conservator
 Other: Assignor
Signer Is Representing: _____

Signer's Name: _____
 Corporate Officer -- Title(s): _____
 Partner -- Limited General
 Individual Attorney in Fact
 Trustee Guardian or Conservator
 Other: _____
Signer Is Representing: _____

**EXHIBIT A
PATENT ASSETS**

SuVolta patent assets – U.S.

SuVolta confidential						
#	SuVolta Doc# of No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
1	10-001 US	Electronic Devices and Systems, and Methods for Making and Using the Same	Issued	02-18-2010 12708,497	09-25-2012 8,273,617	3.5 yr. maintenance fee due 2016
2	10-001 CON1	Electronic Devices and Systems, and Methods for Making and Using the Same	Issued	07-19-2012 13653,593	09-24-2013 8,841,824	3.5 yr. maintenance fee due 2017
3	10-001 CON2	Electronic Devices and Systems, and Methods for Making and Using the Same	Issued	09-14-2012 13616,053	12-10-2013 8,604,627	3.5 yr. maintenance fee due 2017
4	10-001 CON3	Electronic Devices and Systems, and Methods for Making and Using the Same	Issued	09-14-2012 13616,859	12-10-2013 8,604,630	3.5 yr. maintenance fee due 2017
5	10-001 CON34	Electronic Devices and Systems, and Methods for Making and Using the Same	Issued	11-16-2013 14083,931	8,976,128	3.5 yr. maintenance fee due 2016
6	10-002 US	Low Power Semiconductor Transistor Structure and Method of Fabrication Thereof	Issued	12-17-2010 12871,864	09-10-2013 8,530,786	3.5 yr. maintenance fee due 2017
7	10-002 CON1	Low Power Semiconductor Transistor Structure and Method of Fabrication Thereof	Filed	08-19-2013 13889,936		
8	10-003 US	Transistor with Threshold Voltage Set Notch and Method of Fabrication Thereof	Issued	12-17-2010 12871,956	09-24-2014 8,769,872	3.5 yr. maintenance fee due 2017
9	10-003 DIV1	Transistor with Threshold Voltage Set Notch and Method of Fabrication Thereof	Filed	08-06-2014 14296,827		
10	10-004 DIV1	Process for Manufacturing an Improved Analog Transistor	Issued	07-20-2012 13663,902	06-10-2014 8,748,218	3.5 yr. maintenance fee due 2017
11	10-004 DIV2	Analog Transistor	Filed	05-09-2014 14273,936		Office action response to be filed by SuVolta 2/23/16
12	10-005 US	Semiconductor Structure and Method of Fabrication Thereof with Mixed Metal Types	Issued	12-03-2010 12660,266	10-23-2013 8,569,128	3.5 yr. maintenance fee due 2017
13	10-005 CON1	Semiconductor Structure and Method of Fabrication Thereof with Mixed Metal Types	Filed	10-04-2013 14046,234		Office action response due 6/4/16 (indication of allowable claims)
14	10-007 US	Semiconductor Structure with Improved Channel Stack and Method for Fabrication Thereof	Issued	03-03-2011 13039,866	09-03-2013 8,528,271	3.5 yr. maintenance fee due 2017

#	SuVola DocId No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
15	10-007 CON1	Semiconductor Structure with Improved Channel Stack and Method for Fabrication Thereof	Filed	07-31-2013 13065,787		
16	10-009 U0	Source/Drain Extension Control for Advanced Transistors	Issued	12-03-2010 12060,269	03-26-2013 8,404,551	3.5 yr. maintenance fee due 2016
17	10-009 CON1	Source/Drain Extension Control for Advanced Transistors	Issued	02-19-2013 13770,313	10-20-2013 8,563,364	3.5 yr. maintenance fee due 2017
18	10-009 CON2	Source/Drain Extension Control for Advanced Transistors	Issued	09-18-2013 14030,471	04-01-2014 8,686,511	3.5 yr. maintenance fee due 2017
19	10-009 CON3	Source/Drain Extension Control for Advanced Transistors	Allowed	02-24-2014 14108,493		issue fee to be paid by SuVola on 3/2/15
20	D01A-0010 CON2	Circuit Configurations Having Four Terminal Devices	Issued	08-23-2010 12081,659	07-26-2011 7,986,107	3.5 yr. maintenance fee paid 2016
21	10-011 U0	Method for Minimizing Defects in a Semiconductor Substrate due to Ion Implantation	Issued	09-30-2010 12055,657	02-19-2013 8,377,807	3.5 yr. maintenance fee due 2016
22	10-012 U0	Method for Reducing Punch-Through in a Transistor Device	Issued	09-30-2010 12055,666	02-19-2013 8,377,763	3.5 yr. maintenance fee due 2016
23	10-013 U0	Method for Minimizing Defects in a Semiconductor Substrate due to Ion Implantation	Issued	09-30-2010 12055,730	10-14-2014 8,859,618	3.5 yr. maintenance fee due 2016
24	10-014 U0	Advanced Transistors with Punch Through Suppression	Issued	09-30-2010 12055,813	04-16-2013 8,421,162	3.5 yr. maintenance fee due 2016
25	10-014 DIV1	Advanced Transistors with Punch Through Suppression	Filed	02-24-2014 14108,216		
26	10-015 U0	Advanced Transistors with Threshold Voltage Set Dopant Structures	Filed	09-30-2010 12055,765		Office action response due 3/10/15 (SuVola will respond)
27	11-021 U0	Digital Circuits having Improved Transistors, and Methods Thereof	Issued	02-18-2011 13030,939	05-14-2013 8,461,576	3.5 yr. maintenance fee due 2016
28	11-021 CON1	Digital Circuits having Improved Transistors, and Methods Thereof	Filed	05-10-2013 13091,929		
29	11-024 U0	Analog Circuits having Improved Transistors, and Methods Thereof	Issued	03-24-2011 13071,369	03-19-2013 8,400,219	3.5 yr. maintenance fee due 2016

#	SuVola DocId No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
30	11-024 CON1	Analog Circuits having Improved Transistors, and Methods Thereof	Issued	02-15-2013 13770,482	05-30-2014 8,647,624	3.5 yr. maintenance fee due 2016
31	11-024 CON2	Analog Circuits having Improved Transistors, and Methods Thereof	Filed	09-29-2014 14000,236		
32	11-025 U0	Circuit Devices and Methods Having Adjustable Transistor Body Bias	Allowed	06-23-2011 13167,625		Notice of allowance received (SuVola will pay issue fee)
33	11-028 U0	Electronic Device with Controlled Threshold Voltage	Issued	07-26-2012 13659,554	05-10-2014 8,748,555	3.5 yr. maintenance fee due 2017
34	11-028 CON1	Electronic Device with Controlled Threshold Voltage	Issued	05-30-2014 14292,806	6,963,249	3.5 yr. maintenance fee due 2016
35	11-032 U0	Porting a Circuit Design from a First Semiconductor Process to a Second Semiconductor Process	Issued	08-29-2012 13692,122	02-04-2014 8,546,676	3.5 yr. maintenance fee due 2017
36	11-032 CON1	Porting a Circuit Design from a First Semiconductor Process to a Second Semiconductor Process	Issued	02-04-2014 14171,224	08-12-2014 8,806,395	3.5 yr. maintenance fee due 2016
37	11-032 CON2	Porting a Circuit Design from a First Semiconductor Process to a Second Semiconductor Process	Filed	07-21-2014 14036,793		
38	11-033 U0	Tipless Transistors, Short-Tip Transistors, and Methods and Circuits Thereof	Issued	12-05-2012 13708,983	11-25-14 8,899,327	3.5 yr. maintenance fee due 2016
39	11-033 DIV1	Tipless Transistors, Short-Tip Transistors, and Methods and Circuits Thereof	Filed	11-05-2014 14033,414		
39	11-034 U0	Transistor with Reduced Scattered Dopants	Filed	05-11-2012 13469,593		Office action response due 4/1/16 (SuVola to respond early March)
40	11-035 U0	Integrated Circuit Devices and Methods	Issued	05-14-2012 13471,353	08-12-2014 8,611,069	3.5 yr. maintenance fee due 2016
41	11-035 CON1	Integrated Circuit Devices and Methods	Filed	08-09-2014 14055,892		
42	11-036 U0	Epitaxial Channel Transistors and Die with Diffusion Doped Channels	Filed	05-11-2012 13469,201		
43	11-038 U01	Transistor having Reduced Junction Leakage and Methods of Forming Thereof	Issued	12-21-2012 13725,162	11-11-14 8,893,609	3.5 yr. maintenance fee due 2016
44	11-038 DIV1	High Uniformity Screens and Epitaxial Layers for CMOS Devices	Filed	11-06-2014 14634,595		

#	SuVola Docket No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
45	11-037 US	Analog Circuits having Improved Insulated Gate Transistors, and Methods Thereof	Filed	10-05-2012 13646,306		FCE to be filed week of 2/23/15 (SuVola will file)
46	11-038A US	Monitoring and Measurement of Thin Film Layers	Issued	08-11-2012 13469,898	08-06-2014 6,796,046	3.5 yr. maintenance fee due 2015
47	11-038A CON1	Monitoring and Measurement of Thin Film Layers	Filed	06-11-2012 14001,512		
48	11-039 US	Semiconductor Structure with Substitutional Boron and Method for Fabrication Thereof	Allowed	06-11-2012 13469,249		Issue fee to be paid 3/2/2015 (SuVola will pay)
49	11-040 US	Reusing or Eliminating Pre-Amorphization in Transistor Manufacture	Issued	05-16-2012 13473,403	10-29-2013 8,669,166	3.5 yr. maintenance fee due 2017
50	11-040 CON1	Reusing or Eliminating Pre-Amorphization in Transistor Manufacture	Issued	10-04-2013 14046,147	04-22-16 8,937,005	3.5 yr. maintenance fee due 2018
	11-040 CON2	Reusing or Eliminating Pre-Amorphization in Transistor Manufacture	Filed	01-20-2015		
51	11-041 US	CMOS Gate Stack Structures and Processes	Issued	06-05-2012 13469,824	05-27-2014 8,735,807	3.5 yr. maintenance fee due 2017
52	11-041 CON1	CMOS Gate Stack Structures and Processes	Filed	04-09-2014 14266,116		
53	11-042 US	Body Bias Circuits and Methods	Issued	11-02-2012 13669,063	08-26-2014 8,816,754	3.5 yr. maintenance fee due 2018
54	11-042 DIV1	Body Bias Circuits and Methods	Filed	09-19-2014 14460,329		
55	11-043 US	Semiconductor Devices having Pin Structures and Fabrication Methods Thereof	Allowed	02-05-2014 14179,570		Issue fee due 8/5/15
56	11-044 US	Circuits and Methods for Measuring Circuit Elements in an Integrated Circuit Device	Issued	12-23-2011 13036,434	12-03-2013 8,699,623	3.5 yr. maintenance fee due 2017
57	11-044 CON1	Circuits and Methods for Measuring Circuit Elements in an Integrated Circuit Device	Issued	11-05-2013 14072,761	09-16-2014 8,837,239	3.5 yr. maintenance fee due 2017
58	11-044 CON2	Circuits and Methods for Measuring Circuit Elements in an Integrated Circuit Device	Filed	09-15-2014 14467,663		

#	SuVola Docket No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
59	11-045 US	Deeply Depleted MOS Transistors having a Screening Layer and Methods Thereof	Filed	09-05-2013 14019,107		
60	11-046 US	Multiple Transistor Types Formed in a Common Epitaxial Layer by Differential Out-Diffusion from a Doped Underlayer	Issued	01-30-2012 13459,974	01-14-2014 8,629,016	3.5 yr. maintenance fee due 2017
61	11-046 CON1	Multiple Transistor Types Formed in a Common Epitaxial Layer by Differential Out-Diffusion from a Doped Underlayer	Issued	09-21-2012 13624,449	02-18-2014 8,683,604	3.5 yr. maintenance fee due 2017
62	11-046 CON2	Multiple Transistor Types Formed in a Common Epitaxial Layer by Differential Out-Diffusion from a Doped Underlayer	Issued	02-14-2014 14180,898	0,916,937	3.5 yr. maintenance fee due 2018
	11-046 CON3	Multiple Transistor Types Formed in a Common Epitaxial Layer by Differential Out-Diffusion from a Doped Underlayer	Filed	12-16-2014		
63	11-050 US	CMOS Structures and Processes Based on Selective Thinning	Issued	06-22-2012 13691,787	12-24-2013 8,614,128	3.5 yr. maintenance fee due 2017
64	11-050 CON1	CMOS Structures and Processes Based on Selective Thinning	Filed	12-10-2013 14101,691		Abandoned
	11-050 DIV	CMOS Structures and Processes Based on Selective Thinning	Filed	12-15-2014		
65	11-051 US	Tools and Methods for Yield-Aware Semiconductor Manufacturing Process Target Generation	Issued	09-17-2012 13621,693	04-29-2014 8,719,611	3.5 yr. maintenance fee due 2017
66	11-051 CON1	Tools and Methods for Yield-Aware Semiconductor Manufacturing Process Target Generation	Filed	01-28-2014 14263,849		
67	11-052 US	Integrated Circuits having a Purity of High-K Metal Gate FETs with Various Combinations of Channel Foundation Structure and Gate Stack Structure and Methods of Making Same	Filed	01-31-2013 13765,897		Waiting to hear from patent office
68	11-054 US	Unopposed Channel Transistor with Parameters Matched to a Doped Channel Transistor	Filed	05-03-2013 13867,142		Waiting to hear from patent office
69	11-055 US	Integrated Circuits having a Purity of Metal Gate FETs with Precisely Set Work Functions through Combinations of Channel Structure and Metal Gate Layering	Filed	11-15-2012 13677,767		Office action response due 3/15/15 (SuVola will respond)
70	11-056 US	Memory Circuits and Methods of Making and Designing the Same	Issued	12-14-2012 13716,020	03-26-2014 8,619,603	3.5 yr. maintenance fee due 2016
71	11-056 CON1	Memory Circuits and Methods of Making and Designing the Same	Filed	05-16-2014 14280,318		

#	SuVolla Docket No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
72	11-056 CIV1	Memory Circuits and Methods of Making and Designing the Same	Filed	09-16-2014 16451,442		
73	12-057 US	Method for Substrate Preservation During Transistor Fabrication	Issued	05-29-2012 13482,394	07-15-2014 8,378,765	3.5 yr. maintenance fee due 2015
74	12-058 US	Process For Manufacture of Integrated Circuits with Different Channel Doping Transistor Architectures and Devices Thereof	Issued	01-23-2013 13748,418	11-04-2014 8,877,619	3.5 yr. maintenance fee due 2015
75	12-059 US	Circuits and Devices for Generating Bi-Directional Body Bias Voltages, and Methods Therefor	Allowed	01-22-2013 13747,355		Issue fee paid, expect issue notification approx. 3/1
76	12-080 US	Method for Fabricating Multiple Transistor Devices on a Substrate with Varying Threshold Voltages	Filed	02-28-2012 13407,827		Office action response due 3/29/15 (SuVolla will respond)
77	12-082 US	Semiconductor Structure with Multiple Transistors Having Various Threshold Voltages and Method of Fabrication Thereof	Filed	05-25-2013 13925,555		Waiting to hear from patent office
78	12-063 US	Semiconductor Devices with Dopant Migration Suppression and Method of Fabrication Thereof	Filed	09-18-2012 13822,194		Office action response due 3/24/15 (SuVolla will respond)
79	12-054A	DRAM Cell Layout Structure and Devices Thereof	Issued	02-26-2013 13776,912	10-14-2014 8,863,684	3.5 yr. maintenance fee due 2015
80	12-064A CIV1	DRAM Cell Layout Structure and Devices Thereof	Filed	10-10-2014 140511,487		
81	12-065 US	Semiconductor Structure with Reduced Junction Leakage and Method of Fabrication Thereof	Issued	08-31-2012 13660,647	01-28-2014 8,537,856	3.5 yr. maintenance fee due 2017
82	12-065 CON1	Semiconductor Structure with Reduced Junction Leakage and Method of Fabrication Thereof	Filed	12-19-2013 14133,743		Office action response due 3/12/15 (SuVolla will respond)
83	12-088 US	Integrated Circuit Device Methods and Models with Predicted Device Metro Variations	Filed	02-28-2013 13780,006		
84	12-058 US	DRAM-Type Device with Low Variation Transistor Peripheral Circuits, and Related Methods	Filed	10-31-2013 14055,755		Response requirements response due 3/21/15 (SuVolla will respond)
85	12-059 US	Integrated Circuit Process and Bias Monitors and Related Methods	Filed	12-29-2013 14135,258		Office action response due 4/28/15 (SuVolla will respond)
86	12-070 US	Slow Based Process and Bias Monitors and Related Methods	Filed	11-15-2013 14081,264		Office action response due for 4/30/15 (SuVolla will respond)
87	12-071 US	Bi-Interleaved Low Voltage 6-T1 GRAM and Related Methods	Allowed	12-12-2013 14104,182		Issue fee due 8/4/15

#	SuVolla Docket No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
88	12-072 US	Ring Oscillator with N/KOS or P/KOS Variation Insensitivity	Allowed	03-08-2013 13792,005		Issue fee paid, waiting for issue notification
89	13-076 US	Method for Fabricating a Transistor Device with a Tuned Dopant Profile	Filed	03-14-2013 13828,262		
90	13-075 US	Integrated Circuit Device Body Bias Circuits and Methods	Filed	03-15-2013 13835,221		
91	13-077 US	Multiple VDD Clock Buffer	Allowed	03-01-2013 13783,167		Issue fee paid, waiting for issue notification
92	13-078 US	Transistor Array Structure	Filed	03-19-2013 13835,327		
93	13-080 US	Buried Channel Deeply Depleted Channel Transistor	Filed	05-23-2014 14285,063		
94	13-081 US	Architecture and Fabrication Method for DDC Transistors	Filed	05-25-2014 14015,232		
95	13-093 US	DRAM Performance Monitor	Filed	06-20-2013 14014,978		3.5 yr. maintenance fee due 2016
96	13-084 US	Fabrication Method for Deeply Depleted Channel and Other Devices Using Selective Epitaxial Growth	Filed	06-20-2014 14463,813		
97	13-086 PRO	Flash Device Fabrication Method for Deeply Depleted Channel and Other Devices	Filed	11-27-2013 61959,910		* Abandoned
98	13-087 PRO	Structure and Method for Reducing Junction Leakage in a Transistor Device	Filed	02-16-2014 61941,093		* Abandoned
99	13-089 PRO	Methods for Achieving Multiple Program and Erase States in Flash Memory using a Four-Terminal Transistor	Filed	12-12-2013 61915,418		* Abandoned
100	14-090 PRO	Buried Depleted Barrier for Migrated Source Drain Junction Leakage Transistors	Filed	03-31-2014 61972,507		* Utility conversion due 3/31/15
101	14-091 PRO	Structure and Method for Reducing Junction Leakage in a Transistor Device	Filed	02-11-2014 61938,229		* Abandoned
102	14-092 US	Power Up Body Bias Circuits and Methods	Filed	07-28-2014 14341,733		
103	14-093 PRO	Three Dimensional Flash Memory Structures and Methods of Making the Same	Filed	02-12-2014 61938,941		* Abandoned
104	14-094 PRO	Structure and Method for Reducing Leakage in a Transistor Device	Filed	03-05-2014 61949,784		* Conversion to utility due 3/8/2015

#	ZuVolla DocRef No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
105	14-035 UG	Operational Amplifier Input Offset Correction with Transistor Threshold Voltage Adjustment	Filed	06-19-2014 141463,568		
						Provisional applications have not been done. FSL file has option for the new patent applications.
#	IBM DocRef No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
1	0001	Integrated Circuit using Complementary Junction Field Effect Transistor and MOS Transistor in Silicon and Silicon Alloys	Issued	10-28-2005 11281,873	08-04-2009 7,559,673	
2	0001-DIV1	Integrated Circuit using Complementary Junction Field Effect Transistor and MOS Transistor in Silicon and Silicon Alloys	Issued	06-26-2009 121492,320	03-29-2011 7,915,107	
3	0002	Method of Producing and Operating a Low Power Junction Field Effect Transistor	Issued	12-07-2005 11535,054	01-06-2009 7,474,128	
4	0003	Semiconductor Device, Design Method and Structure	Issued	10-31-2005 11590,255	04-29-2009 7,526,163	
5	0003-DIV1	Semiconductor Device, Design Method and Structure	Issued	02-26-2009 12080,497	05-21-2011 7,984,920	
6	0003-DIV2	Semiconductor Device, Design Method and Structure	Issued	02-26-2009 12080,490	05-25-2011 7,969,393	
7	0005	Self Aligned Gate JFET Structure and Method	Issued	06-09-2005 11450,112	07-14-2009 7,550,755	
8	0005-DIV1	Self Aligned Gate JFET Structure and Method	Issued	09-23-2008 12236,164	03-30-2010 7,587,335	
9	0006	Scalable Process and Structure for JFET for Small and Decreasing Line Widths	Issued	06-12-2005 11451,865	01-05-2010 7,642,666	
10	0010	Circuit Configurations Having Four Terminal JFET Devices	Issued	05-12-2005 11462,442	03-22-2009 7,592,641	
11	0010-DIV1	Circuit Configurations Having Four Terminal JFET Devices	Issued	07-21-2009 12565,445	03-22-2010 7,804,332	

DSM Patent assets – U.S. (see also rows 1-11 immediately above)

#	Bu/Volta Doc# No.	Title	Status	Filing Date Serial No.	Issued Date Patent No.	Notes
12	0014	Semiconductor Device Having a PIN Structure and Fabrication Method Thereof	Issued	06-02-2006 12/114,183	08-10-2010 7,772,619	
13	0019	Integrated Circuit Using Complementary Junction Field Effect Transistor and MOS Transistor in Silicon and Silicon Alloys	Issued	11-03-2006 12/263,854	03-30-2010 7,597,834	
14	0022	JFET with Built-in Back Gate in either SOI or Bulk Silicon	Issued	06-10-2006 11/602,172	07-07-2009 7,567,393	
15	0023-DIV1	JFET with Built-in Back Gate in either SOI or Bulk Silicon	Issued	11-14-2008 12/270,564	01-12-2010 7,846,654	
16	0023	Oxide Isolated Metal Silicon-Gate JFET	Issued	07-11-2005 11/484,402	12-15-2009 7,633,101	
17	0023-DIV1	Method of Forming an Oxide Isolated Metal Silicon-Gate JFET	Issued	11-24-2008 12/216,574	05-11-2010 7,783,804	
18	0026	Level Shifting Circuit Having Junction Field Effect Transistors	Issued	07-28-2006 11/456,908	01-12-2010 7,646,233	
19	0031	Junction Field Effect Transistor Input Buffer Level Shifting Circuit	Issued	09-01-2006 11/616,252	06-29-2010 7,746,146	
20	0032	Semiconductor Device Including a Bias Voltage Generator	Issued	05-14-2007 11/818,398	03-16-2010 7,679,427	
21	0035	Circuit and Method for Generating Electrical Signals with Junction Field Effect Transistors	Issued	09-21-2007 11/933,296	07-27-2010 7,764,137	
22	0041	Back-Gate JFET with Reduced Area Consumption and Fabrication Method Thereof	Issued	04-30-2006 12/143,118	07-08-2011 7,993,344	
23	0043	Semiconductor Device Storage Cell Structure, Method of Operation and Method of Manufacture	Issued	05-01-2007 11/799,572	04-06-2010 7,692,829	
24	0044	Image Sensing Cell, Device, Method of Operation, and Method of Manufacture	Issued	05-01-2007 11/799,571	05-01-2010 7,727,821	
25	0049	Common Data Line Signaling and Method	Issued	07-02-2007 11/824,737	08-10-2011 7,941,096	
26	0051	Method and Apparatus for Improving SRAM Write Operations	Issued	12-19-2009 12/039,684	12-07-2010 7,649,139	
27	0057A	Method for Applying a Stress Layer to a Semiconductor Device and Device Formed Therefrom	Issued	05-04-2007 11/744,617	11-18-2009 7,469,107	
28	0057B	Semiconductor Device Having Strain-Inducing Substrate and Fabrication Methods Thereof	Issued	05-04-2007 11/744,669	05-18-2009 7,631,654	

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29	0097B-DIV1	Semiconductor Device Having Strain-Inducing Substrate and Fabrication Methods Thereof	Issued	07-23-2009 12/170,891	10-20-2009 7,605,031	
30	0067	System and Method for Detecting Multiple Malches	Issued	03-29-2007 11/653,441	04-06-2010 7,694,069	
31	0069	Content Addressable Memory Cell Including a Junction Field Effect Transistor	Issued	05-01-2007 11/769,305	05-01-2010 7,729,149	
32	0070	Junction Field Effect Dynamic Random Access Memory Cell and Content Addressable Memory Cell	Issued	05-17-2007 11/804,132	12-15-2009 7,633,784	
33	0074	System and Method for Routing Connections	Issued	12-19-2007 11/910,482	03-30-2010 7,689,964	
34	0075	System and Method for Routing Connections with Improved Interconnect Thickness	Issued	05-06-2008 12/115,528	10-18-2011 8,042,076	
35	0078	JFET Device with Improved Off-State Leakage Current and Method of Fabrication	Issued	05-03-2007 11/744,690	04-28-2009 7,625,138	
36	0078-DIV1	JFET Device with Improved Off-State Leakage Current and Method of Fabrication	Issued	07-23-2008 12/178,404	05-04-2010 7,709,311	
37	0079	Current-Limited Output Buffer	Issued	07-16-2008 12/173,405	06-23-2010 7,741,802	
38	0082	Swapped-Body RAM Architecture	Issued	12-17-2007 11/950,032	05-22-2010 7,742,328	
39	0084	Transistor Providing Different Threshold Voltages and Method of Fabrication Thereof	Issued	05-03-2007 11/743,973	01-12-2010 7,648,562	
40	0084-DIV1	Transistor Providing Different Threshold Voltages and Method of Fabrication Thereof	Issued	03-02-2009 12/053,785	11-30-2010 7,843,016	
41	0085	JFET Device with Virtual Source and Drain Link Regions and Method of Fabrication	Issued	05-03-2007 11/744,129	04-28-2009 7,625,139	
42	0087	Switching Circuits and Methods for Programmable Logic Devices	Issued	03-03-2007 11/669,977	12-08-2009 7,629,812	
43	0094	Method to Fabricate Gate Electrodes	Issued	02-19-2008 12/033,487	01-19-2010 7,646,899	
44	0097	Programmable Switch Circuit and Method, Method of Manufacture, and Devices and Systems Including the Same	Issued	05-03-2008 12/155,865	05-04-2010 7,710,148	
45	0098	Method for Manufacturing a Junction Field Effect Transistor Having a Double Gate	Issued	12-02-2008 12/026,415	09-15-2011 8,017,475	

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46	0088-CON	Junction Field Effect Transistor Having a Double Gate Structure	Issued	08-26-2011 13/210,809	09-18-2012 8,264,817	
47	0100	Level-Shifting Circuit with Bipolar Junction Transistor	Issued	08-21-2008 12/155,729	03-30-2010 7,658,111	
48	0101	Voltage-Level Transistor	Issued	07-11-2008 12/171,905	07-06-2010 7,750,735	
49	0105	Dynamic Random Access Memory Having Junction Field Effect Transistor Cell Access Device	Issued	08-20-2008 12/184,651	10-11-2011 8,035,139	
50	0124	Memory Cell Including an Emitter Follower and Emitter Follower Sensing Scheme and Method of Reading Data Therefrom	Issued	09-18-2008 12/284,037	11-30-2010 7,843,727	
51	0125	Junction Field Effect Transistor (JFET) Structure Having Top-To-Bottom Gate Tie and Method of Manufacture	Issued	12-17-2008 12/916,344	05-17-2011 7,943,971	
52	0128	Semiconductor Device with Multiple Transistors Formed in a Partially Depleted Semiconductor-On-Insulator Substrate	Issued	02-05-2009 12/356,791	12-07-2010 7,847,354	
53	0132	Junction Field Effect Transistor Using a Silicon on Insulator Architecture	Issued	07-25-2008 12/160,155	09-10-2010 7,772,620	
54	0139	Method for Providing Temperature Uniformity of Rapid Thermal Annealing	Issued	02-11-2009 12/369,169	09-04-2011 8,012,873	
55	0144	Method and Apparatus for Improving DRAM Write Operations	Issued	12-19-2008 12/039,618	06-28-2011 7,989,759	
56	0146	Advanced JFET with Reliable Channel Control and Method of Manufacture	Issued	01-07-2009 12/349,747	05-18-2010 7,736,962	

SuVolta patent assets -- PCT

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1	10-001 PCT1	Electronio Devices and Systems, and Methods for Making and Using the Same	09-15-2010 US2010/048999	National Stage	04-07-2011 WO 2011/041100	
2	10-001 PCT2	Electronio Devices and Systems, and Methods for Making and Using the Same	09-16-2010 US2010/049000	National Stage	04-07-2011 WO 2011/041110	
3	10-001 PCT4	Electronio Devices and Systems, and Methods for Making and Using the Same	11-09-2010 US2010/085702	National Stage	09-28-2011 WO 2011/082799	
4	10-001 PCT5	Electronio Devices and Systems, and Methods for Making and Using the Same	02-17-2011 US2011/025279	National Stage	09-26-2011 WO 2011/093314	
5	10-001 PCT6	Electronio Devices and Systems, and Methods for Making and Using the Same	02-17-2011 US2011/028284	National Stage	09-26-2011 WO 2011/093319	
6	10-002 PCT	Low Power Semiconductor Transistor Structure and Method of Fabrication Thereof	04-07-2011 US2011/031631	National Stage	10-20-2011 WO 2011/130888	
7	10-003 PCT	Transistor with Threshold Voltage Set Notch and Method of Fabrication Thereof	09-21-2011 US2011/041107	National Stage	12-29-2011 WO 2011/103171	
8	10-007 PCT	Semiconductor Structure with Improved Channel Stack and Method for Fabrication Thereof	02-20-2012 US2012/027053	National Stage	09-07-2012 WO 2012/119873	
9	10-008 PCT	Source/Drain Extension Control for Advanced Transistors	11-30-2011 US2011/052495	National Stage	10-29-2012 WO 2012/146026	
10	10-014 PCT	Advanced Transistors with Punch Through Suppression	09-21-2011 US2011/041185	National Stage	12-29-2011 WO 2011/103109	
11	10-016 PCT	Advanced Transistors with Threshold Voltage Set Dopant Structures	09-21-2011 US2011/041159	National Stage	12-29-2011 WO 2011/103164	
12	10-018 PCT	Advanced Transistors with Structured Low Dopant Channels	11-05-2010 US2010/055690	National Stage	05-12-2012 WO 2012/090639	
13	11-043 PCT	Semiconductor Devices having Fin Structures and Fabrication Methods Thereof	09-03-2012 US2012/046931	National Stage	02-14-2013 WO 2013/022753	
14	11-046 PCT	Deeply Depleted MOS Transistors having a Screening Layer and Methods Thereof	09-17-2013 US2013/030046	Filed		National phase filing due 3/21/16 -- CN, KR
15	12-002 PCT	Semiconductor Structure with Multiple Transistors having Various Threshold Voltages and Method of Fabrication Thereof	09-28-2013 US2013/047767	Filed		Did not file National
16	12-008 PCT	DRAM-Type Device with Low Variation Transistor Peripheral Circuits, and Related Methods	10-31-2013 US2013/067832	Filed		National phase filing due 4/30/2016

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1	0001 PCT	Integrated Circuit using Complementary Junction Field Effect Transistor and MOS Transistor in Silicon and Silicon Alloys	10-30-2006 US2006/042139	National Stage	05-10-2007 WO 2007/059486	
2	0002 PCT	Method of Producing and Operating a Low Power Junction Field Effect Transistor.	12-07-2006 US2006/046600	National Stage	08-14-2007 WO 2007/037684	
3	0005 PCT	Self Aligned Gate JFET Structure and Method	08-07-2007 US2007/070580	National Stage	12-21-2007 WO 2007/146734	
4	0008 PCT	Scalable Process and Structure for JFET for Small and Decreasing Line Widths	08-11-2007 US2007/070894	National Stage	12-21-2007 WO 2007/146872	
5	0010 PCT	Circuit Configurations Having Four Terminal JFET Devices	08-19-2007 US2007/071076	National Stage	12-31-2007 WO 2007/149979	
6	0021 PCT	Silicon-on-Insulator (SOI) Junction Field Effect Transistor and Method of Manufacture	08-15-2007 US2007/075983	National Stage	02-28-2008 WO 2008/024935	
7	0022 PCT	JFET with Built-In Back Gate in either SOI or Bulk Silicon	08-09-2007 US2007/076555	National Stage	02-21-2008 WO 2008/021919	
8	0029 PCT	Semiconductor Device with Circuits Formed with Essentially Uniform Pattern Density	09-12-2007 US2007/079210	National Stage	04-10-2008 WO 2008/042600	
9	0083 PCT	Method and System for Adaptive Power Management	08-02-2008 US2008/062338	National Stage	11-13-2008 WO 2008/137628	

SuVolta, DSM patent assets -- China

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#	SuVolta Docket No.	Filing Date CN Application No.	Status	Issued Date Patent No.	Notes
1	10-001 CN1	09-15-2010 201080054379.4	Filed		
2	10-001 CN2	09-15-2010 201080054378.X	Filed		Office action response due 3/10/15 (SuVolta will respond)
3	10-001 CN4	11-08-2010 201080061745.8	Filed		
4	10-001 CN5	02-17-2011 201180018743.8	Filed		Office action response due 4/8/15 (SuVolta will respond)
5	10-001 CN6	02-17-2011 201180018710.3	Filed		Office action response due 4/12/15 (SuVolta will respond)
6	10-003 CN	06-21-2011 201180040485.1	Filed		
7	10-007 CN	02-28-2012 201280017397.4	Filed		
8	10-009 CN	11-30-2011 201180058243.5	Filed		
9	10-014 CN	08-21-2011 201180035830.2	Filed		
10	10-018 CN	08-21-2011 201180035832.1	Filed		
#	DSM Docket No.	Filing Date CN Application No.	Status	Issued Date Patent No.	Notes
1	0001 CN	10-30-2008 200880039832.8	Issued	11-9-2011 ZL 200860039832.8	

SuVolta patent assets -- EP

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#	SuVolta Docket No	Filing Date EP Application No.	Status	Publication Date Publication No.	Notes
1	10-001 EP1	09-15-2010 10821021.2	Filed	08-08-2012 EP2483916	Waiting for search report
2	10-001 EP2	09-15-2010 10821022.0	Filed	08-08-2012 EP2483915	Waiting for search report

DSM patent assets -- India

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#	DSM Docket No.	Filing Date IN Application No.	Status
1	0001 IN	10-30-2006 4201/DELNP/2008	Filed

SuVolta and DSM patent assets -- Japan

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#	SuVolta Docket No.	Filing Date JP Application No.	Status	Issued Date Patent No.	Notes
1	10-001 JP1	09-15-2010 2012-532104	Filed		
2	10-001 JP2	09-15-2010 2012-532105	Filed		
3	10-001 JP4	11-8-2010 2012-539939	Filed		
4	10-001 JP5	02-17-2011 2012-554028	Filed		
5	10-001 JP6	02-17-2011 2012-554029	Filed		
6	10-003 JP	06-21-2011 2013-516664	Filed		
7	10-014 JP	06-21-2011 2013-516663	Filed		
#	DSM Docket No.	Filing Date JP Application No.	Status	Issued Date Patent No.	Notes
1	0010 JP	06-13-2007 2009-515621	Issued	10-05-2012 5,101,610	

SuVolta patent assets -- Korea

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#	SuVolta Docket No	Filing Date KR Application No.	Status	Issued Date Patent No.	Notes
1	10-001 KR1	09-15-2010 10-2012-7011021	Filed		Request for exam due 9/15/15
2	10-001 KR2	09-15-2010 10-2012-7011008	Filed		Request for exam due 9/15/15
3	10-001 KR4	11-08-2010 10-2012-7015629	Filed		Request for exam due 11/8/15
4	10-001 KR5	02-17-2011 10-2012-7024299	Filed		Request for exam due 02/17/16
5	10-001 KR6	02-17-2011 10-2012-7024293	Filed		Request for exam due 2/17/16
6	10-002 KR	04-07-2011 10-2012-7029435	Filed		
7	10-003 KR	06-21-2011 10-2013-7001612	Filed		Request for exam due 6/21/16
8	10-014 KR	06-21-2011 10-2013-7001668	Filed		Request for exam due 6/21/16
9	10-016 KR	06-21-2011 10-2013-7001667	Filed		Request for exam due 6/21/16
10	10-018 KR	11-05-2010 10-2011-7023427	Issued	08-22-2012 10-1178016	
11	11-043 KR	02-28-2014 10-2014-7005446	Filed		Request for exam due 6/4/17

SuVolta and DSM patent assets -- Taiwan

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#	SuVolta Docket No.	Filing Date TW Application No.	Status	Issued Date Patent No.	Notes
1	10-001 TW	09-28-2010 090132965	Filed		
2	10-002 TW	04-11-2011 100112429	Filed		
3	10-003 TW	06-21-2011 100121618	Filed		
4	10-009 TW	12-02-2011 100144358	Filed		Did not seek examination
5	10-014 TW	06-21-2011 100121611	Filed		
6	10-010 TW	06-21-2011 100121612	Filed		
7	11-043 TW	08-08-2012 101126322	Filed		Request for exam due 8/6/15
#	DSM Docket No.	Filing Date TW Application No.	Status	Issued Date Patent No.	Notes
1	0001 TW	10-27-2008 05139730	Issued	11-21-2010 1333695	
2	0082 TW	11-21-2008 97145237	Filed		